

## AFM5000II Control Station for Scanning Probe Microscope

The AFM5000II is a controller for scanning probe microscope control and imaging which allows topological observation and analysis of physical properties in nano-scale regions. Standard inclusion of RealTune II auto-tuning functions for measurement parameters allows acquisition of highly reproducible data.

### Main Features

#### (1) Auto-measurement

A new algorithm developed for prediction and adjustment of major parameters allows one-click measurement simply by pressing the start button.

#### (2) New GUI and analysis functions

Overlaid display of topological and physical property images and the capability for depiction as 3D images provide a visual understanding of the distribution of physical properties.



External appearance